

Application Data Sheet

Application Information

Application Type::	Regular
Subject Matter::	Utility
CD-ROM or CD-R?::	None
Computer Readable Form (CRF)?::	No
Title::	SUBSTRATE INSPECTING METHOD AND SUBSTRATE INSPECTING APPARATUS USING THE METHOD
Attorney Docket Number::	044499-0206
Request for Early Publication?::	No
Request for Non-Publication?::	No
Suggested Drawing Figure::	1
Total Drawing Sheets::	7
Small Entity?::	No
Petition included?::	No
Secrecy Order in Parent Appl.?::	No

Applicant Information

Applicant Authority Type::	Inventor
Primary Citizenship Country::	Japan
Status::	Full Capacity
Given Name::	Kiyoshi
Family Name::	MURAKAMI
City of Residence::	Fukuchiyama-shi, Kyoto-fu
Country of Residence::	Japan

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Country of mailing address:: Japan

Correspondence Information

Correspondence Customer Number:: 22428

E-Mail address:: PTOMailWashington@Foley.com

Representative Information

Representative Customer Number::	22428	
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Domestic Priority Information

Application::	Continuity Type::	Parent Application::	Parent Filing Date::

Foreign Priority Information

Country::	Application number::	Filing Date::	Priority Claimed::
Japan	JP-2003-050357	02/27/2003	Yes

Assignee Information

Assignee name:: Omron Corporation